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PERFORMANCE CHECKSHEET

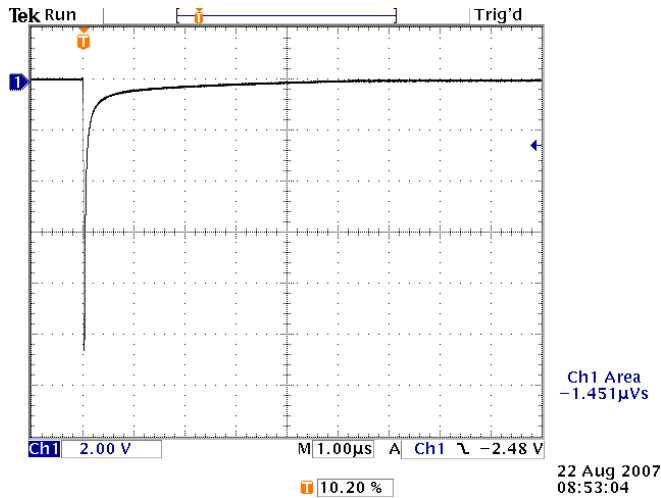
Model: AVR-EB4-B-MSCLA
Type: Semiconductor Device Tester
S.N.: 11809
Date: July 20, 2007

Output Amplitude: to +4A, -4A
Pulse Width (FWHM): 100 us – 1 ms
Switching Time,
+ to -, 20%-80%: ≤ 50 ns
PRF: 1 - 10 Hz
Jitter, Stability: OK
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

Test Waveforms

With a Microsemi UM2106B installed in the AVX-TRRA test jig:

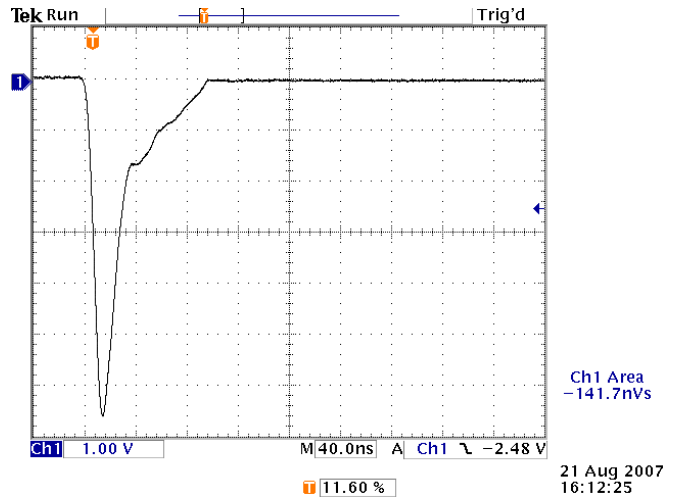


AMP1 = +10 mA, AMP2 = -200V

2 V/div (0.4 A/div), 1 us/div.

Corresponds to a lifetime of 29.0 us (see “Typical Results” section of the manual for discussion).

With a Microsemi UM7102B installed in the AVX-TRRA test jig:



AMP1 = +10 mA, AMP2 = -200V

1 V/div (0.2 A/div), 40 ns/div.

Corresponds to a lifetime of 2.8 us (see “Typical Results” section of the manual for discussion).